

FIG. 1

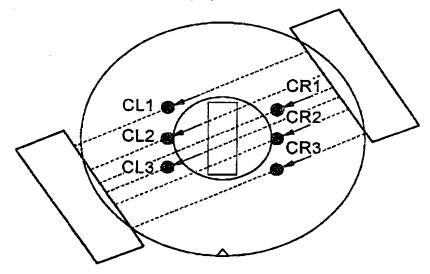


FIG.2

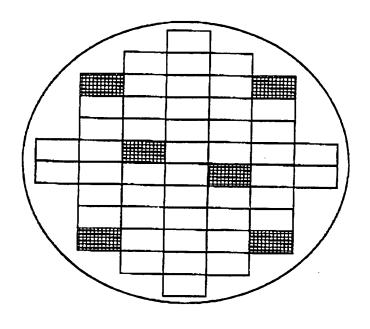
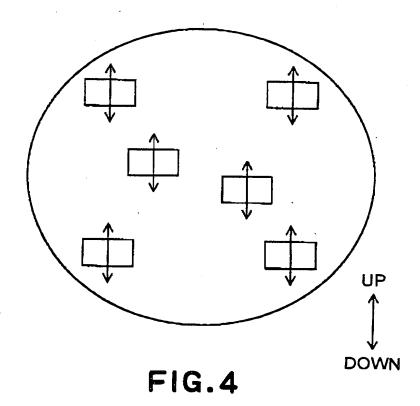


FIG.3



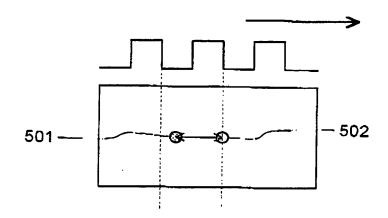


FIG.5

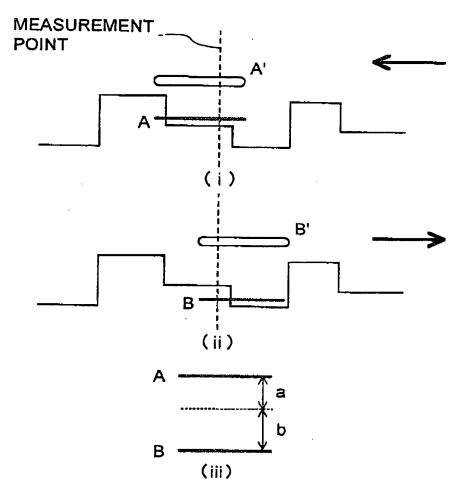


FIG.6

FIG.7A

FIG.7

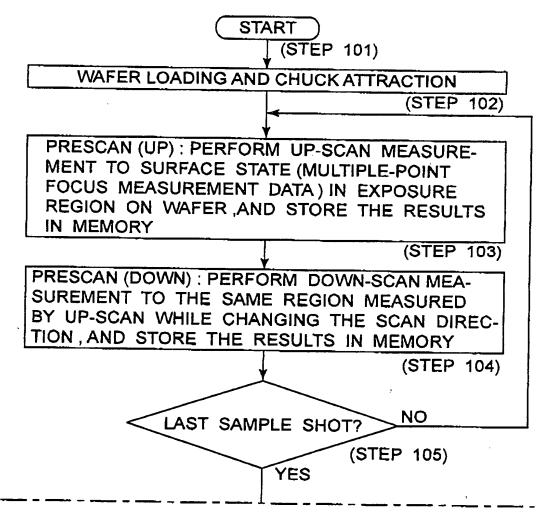


FIG.7A

CALCULATION OF SURFACE-DETECTION FOCUS DATA CORRECTION VALUE: CALCULATE MEA-SUREMENT ERROR & STEP MAGNITUDE CORREC-TION VALUE ON THE BASIS OF THE UP-SCAN AND DOWN-SCAN MEASUREMENT DATA, IN TERMS OF THE DIFFERENCE WITH RESPECT TO BEST FOCUS POSITION

(STEP 106)

SCAN EXPOSURE: CORRECT FOCUS MEASURE-MENT DATA BY USING THE CORRECTION VALUE, CALCULATE CORRECTION VALUE TO THE IMAGE PLANE POSITION, AND CORRECT THE EXPOSURE REGION TOWARD THE IMAGE PLANE

(STEP 107)

RELEASE CHUCK ATTRACTION, AND UNLOAD WAFER (STEP 108)

END (STEP 109)

FIG.7B

FIG.8A

FIG.8

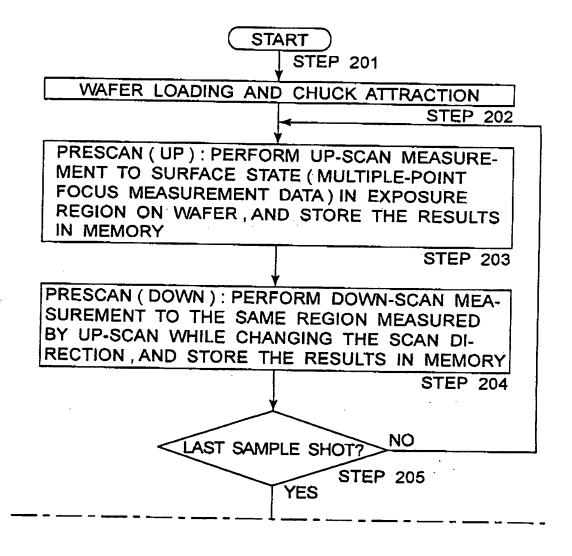


FIG.8A

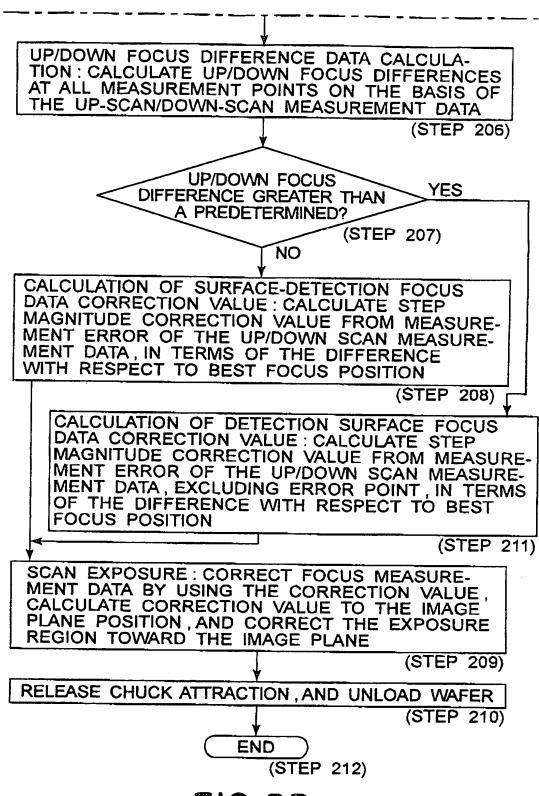


FIG.8B

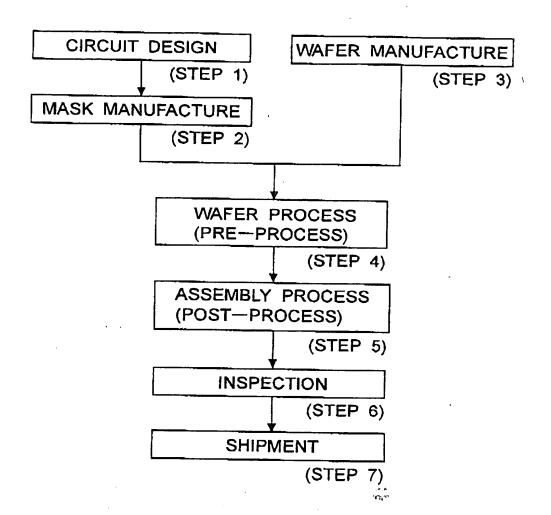


FIG.9

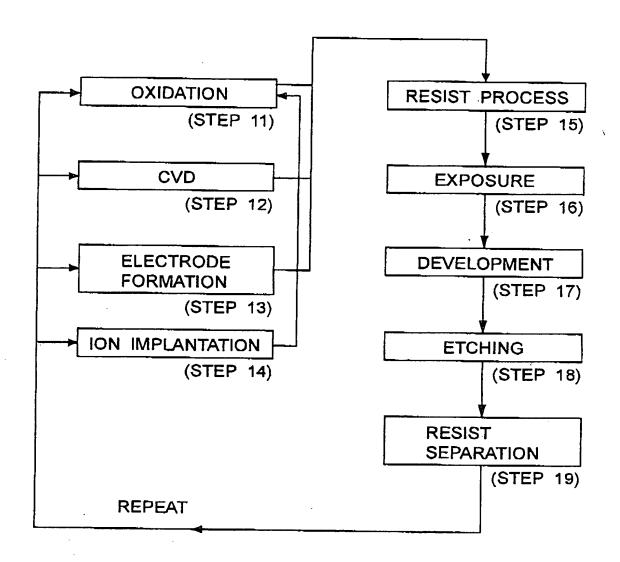


FIG. 10